

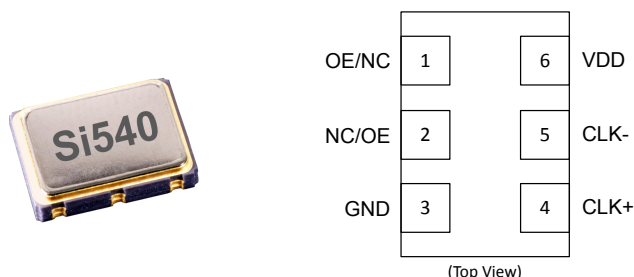


Ultra Series™ Crystal Oscillator Si540 Data Sheet

Ultra Low Jitter Any-Frequency XO (125 fs), 0.2 to 1500 MHz

The Si540 Ultra Series™ oscillator utilizes Silicon Laboratories' advanced 4th generation DSPLL® technology to provide an ultra-low jitter, low phase noise clock at any output frequency. The device is factory-programmed to any frequency from 0.2 to 1500 MHz with <1 ppb resolution and maintains exceptionally low jitter for both integer and fractional frequencies across its operating range. The Si540 offers excellent reliability and frequency stability as well as guaranteed aging performance. On-chip power supply filtering provides industry-leading power supply noise rejection, simplifying the task of generating low jitter clocks in noisy systems that use switched-mode power supplies. Offered in industry-standard 3.2x5 mm and 5x7 mm footprints, the Si540 has a dramatically simplified supply chain that enables Silicon Labs to ship custom frequency samples 1-2 weeks after receipt of order. Unlike a traditional XO, where a different crystal is required for each output frequency, the Si540 uses one simple crystal and a DSPLL IC-based approach to provide the desired output frequency. This process also guarantees 100% electrical testing of every device. The Si540 is factory-configurable for a wide variety of user specifications, including frequency, output format, and OE pin location/polarity. Specific configurations are factory-programmed at time of shipment, eliminating the long lead times associated with custom oscillators.

Pin Assignments



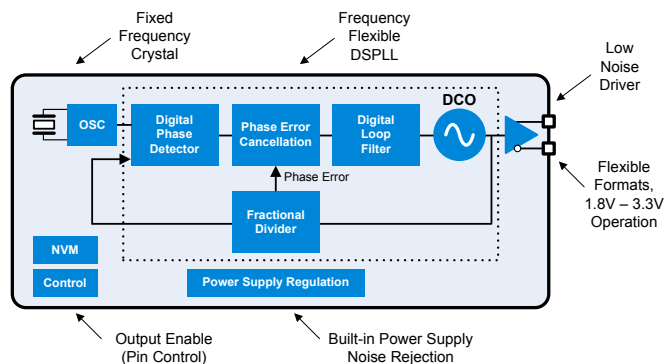
Pin #	Descriptions
1, 2	<i>Selectable via ordering option</i> OE = Output enable; NC = No connect
3	GND = Ground
4	CLK+ = Clock output
5	CLK- = Complementary clock output. Not used for CMOS.
6	VDD = Power supply

KEY FEATURES

- Available with any frequency from 0.2 MHz to 1500 MHz
- Very low jitter: 125 fs Typ RMS (12 kHz – 20 MHz)
- Excellent PSRR and supply noise immunity: –80 dBc Typ
- 7 ppm stability option (–40 to 85°C)
- 3.3 V, 2.5 V and 1.8 V V_{DD} supply operation from the same part number
- LVPECL, LVDS, CML, HCSL, CMOS, and Dual CMOS output options
- 3.2×5, 5×7 mm package footprints
- Any custom frequency available with 1-2 week lead times

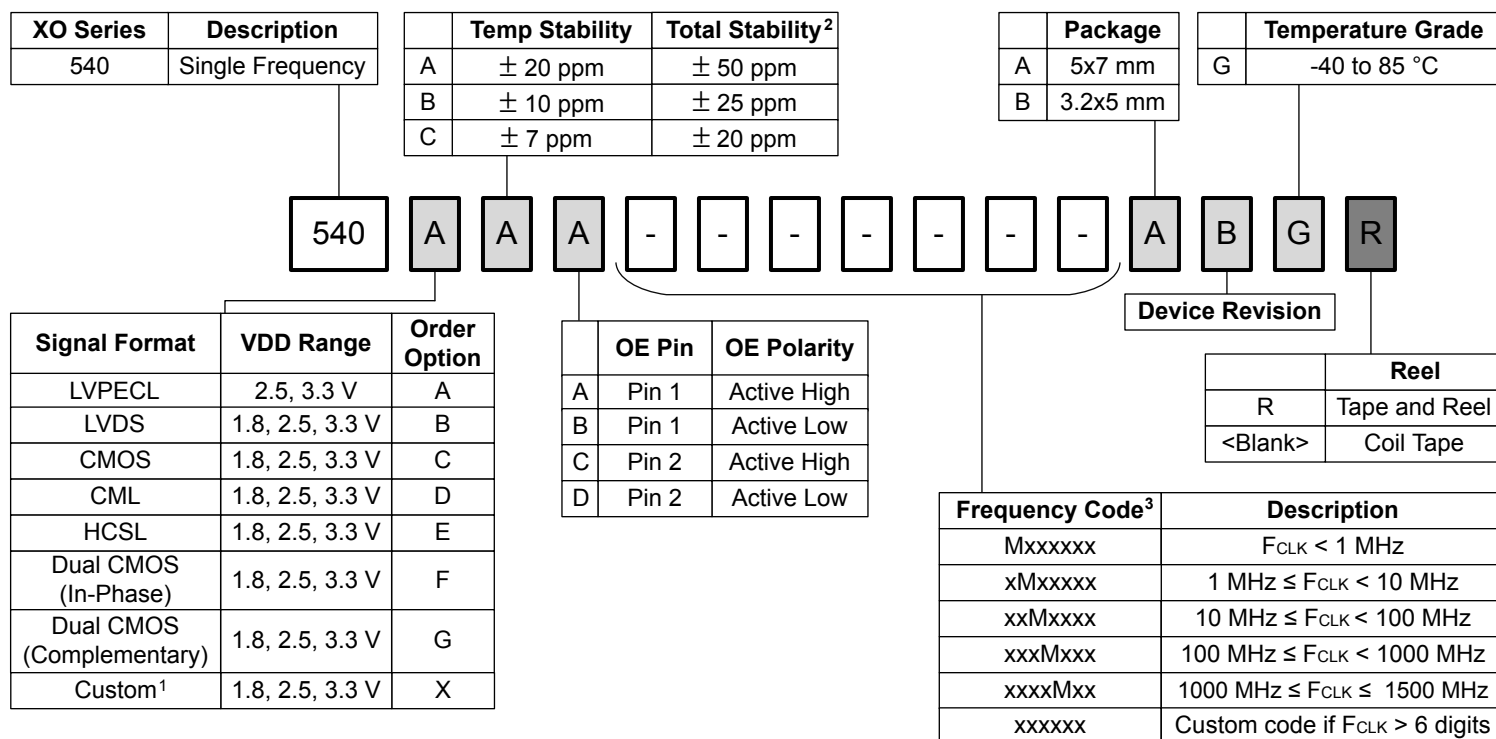
APPLICATIONS

- 100G/200G/400G OTN, coherent optics
- 10G/40G/100G optical ethernet
- 3G-SDI/12G-SDI/24G-SDI broadcast video
- Servers, switches, storage, NICs, search acceleration
- Test and measurement
- Clock and data recovery
- FPGA/ASIC clocking



1. Ordering Guide

The Si540 XO supports a variety of options including frequency, output format, and OE pin location/polarity, as shown in the chart below. Specific device configurations are programmed into the part at time of shipment, and samples are available in 1-2 weeks. Silicon Laboratories provides an online part number configuration utility to simplify this process. Refer to www.silabs.com/oscillators to access this tool and for further ordering instructions.



Notes:

1. Contact Silicon Labs for non-standard configurations.
2. Total stability includes temp stability, initial accuracy, load pulling, VDD variation, and 20 year aging at 70 °C.
3. For example: 156.25 MHz = 156M250; 25 MHz = 25M0000. Create custom part numbers at www.silabs.com/oscillators.

1.1 Technical Support

Frequently Asked Questions (FAQ)	www.silabs.com/Si540-FAQ
Oscillator Phase Noise Lookup Utility	www.silabs.com/oscillator-phase-noise-lookup
Quality and Reliability	www.silabs.com/quality
Development Kits	www.silabs.com/oscillator-tools

2. Electrical Specifications

Table 2.1. Electrical Specifications

$V_{DD} = 1.8\text{ V}, 2.5\text{ V or } 3.3\text{ V} \pm 5\%$, $T_A = -40\text{ to } 85\text{ }^{\circ}\text{C}$

Parameter	Symbol	Test Condition/Comment	Min	Typ	Max	Unit
Temperature Range	T_A		-40	—	85	$^{\circ}\text{C}$
Frequency Range	F_{CLK}	LVPECL, LVDS, CML	0.2	—	1500	MHz
		HCSL	0.2	—	400	MHz
		CMOS, Dual CMOS	0.2	—	250	MHz
Supply Voltage	V_{DD}	3.3 V	3.135	3.3	3.465	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
Supply Current	I_{DD}	LVPECL (output enabled)	—	100	132	mA
		LVDS/CML (output enabled)	—	75	111	mA
		HCSL (output enabled)	—	80	125	mA
		CMOS (output enabled)	—	74	108	mA
		Dual CMOS (output enabled)	—	80	125	mA
		Tristate Hi-Z (output disabled)	—	64	100	mA
Temperature Stability		Frequency stability Grade A	-20	—	20	ppm
		Frequency stability Grade B	-10	—	10	ppm
		Frequency stability Grade C	-7	—	7	ppm
Total Stability ¹	F_{STAB}	Frequency stability Grade A	-50	—	50	ppm
		Frequency stability Grade B	-25	—	25	ppm
		Frequency stability Grade C	-20	—	20	ppm
Rise/Fall Time (20% to 80% V_{PP})	T_R/T_F	LVPECL/LVDS/CML	—	—	350	ps
		CMOS / Dual CMOS ($C_L = 5\text{ pF}$)	—	0.5	1.5	ns
		HCSL, $F_{CLK} > 50\text{ MHz}$	—	—	550	ps
Duty Cycle	D_C	All formats	45	—	55	%
Output Enable (OE) ²	V_{IH}		$0.7 \times V_{DD}$	—	—	V
	V_{IL}		—	—	$0.3 \times V_{DD}$	V
	T_D	Output Disable Time, $F_{CLK} > 10\text{ MHz}$	—	—	3	μs
	T_E	Output Enable Time, $F_{CLK} > 10\text{ MHz}$	—	—	20	μs
Powerup Time	t_{OSC}	Time from $0.9 \times V_{DD}$ until output frequency (F_{CLK}) within spec	—	—	10	ms
LVPECL Output Option ³	V_{OC}	Mid-level	$V_{DD} - 1.42$	—	$V_{DD} - 1.25$	V
	V_O	Swing (diff)	1.1	—	1.9	V_{PP}

Parameter	Symbol	Test Condition/Comment	Min	Typ	Max	Unit
LVDS Output Option ⁴	V _{OC}	Mid-level (2.5 V, 3.3 V VDD)	1.125	1.20	1.275	V
		Mid-level (1.8 V VDD)	0.8	0.9	1.0	V
	V _O	Swing (diff)	0.5	0.7	0.9	V _{PP}
HCSL Output Option ⁵	V _{OH}	Output voltage high	660	750	850	mV
	V _{OL}	Output voltage low	-150	0	150	mV
	V _C	Crossing voltage	250	350	550	mV
CML Output Option (AC-Coupled)	V _O	Swing (diff)	0.6	0.8	1.0	V _{PP}
CMOS Output Option	V _{OH}	I _{OH} = 8/6/4 mA for 3.3/2.5/1.8V VDD	0.85 × V _{DD}	—	—	V
	V _{OL}	I _{OL} = 8/6/4 mA for 3.3/2.5/1.8V VDD	—	—	0.15 × V _{DD}	V

Notes:

1. Total Stability includes temperature stability, initial accuracy, load pulling, VDD variation, and aging for 20 yrs at 70 °C.
2. OE includes a 50 kΩ pull-up to VDD for OE active high. Includes a 50 kΩ pull-down to GND for OE active low. NC (No Connect) pins include a 50 kΩ pull-down to GND.
3. 50 Ω to V_{DD} – 2.0 V.
4. R_{term} = 100 Ω (differential).
5. 50 Ω to GND.

Table 2.2. Clock Output Phase Jitter and PSRRV_{DD} = 1.8 V, 2.5 or 3.3 V ± 5%, T_A = -40 to 85 °C

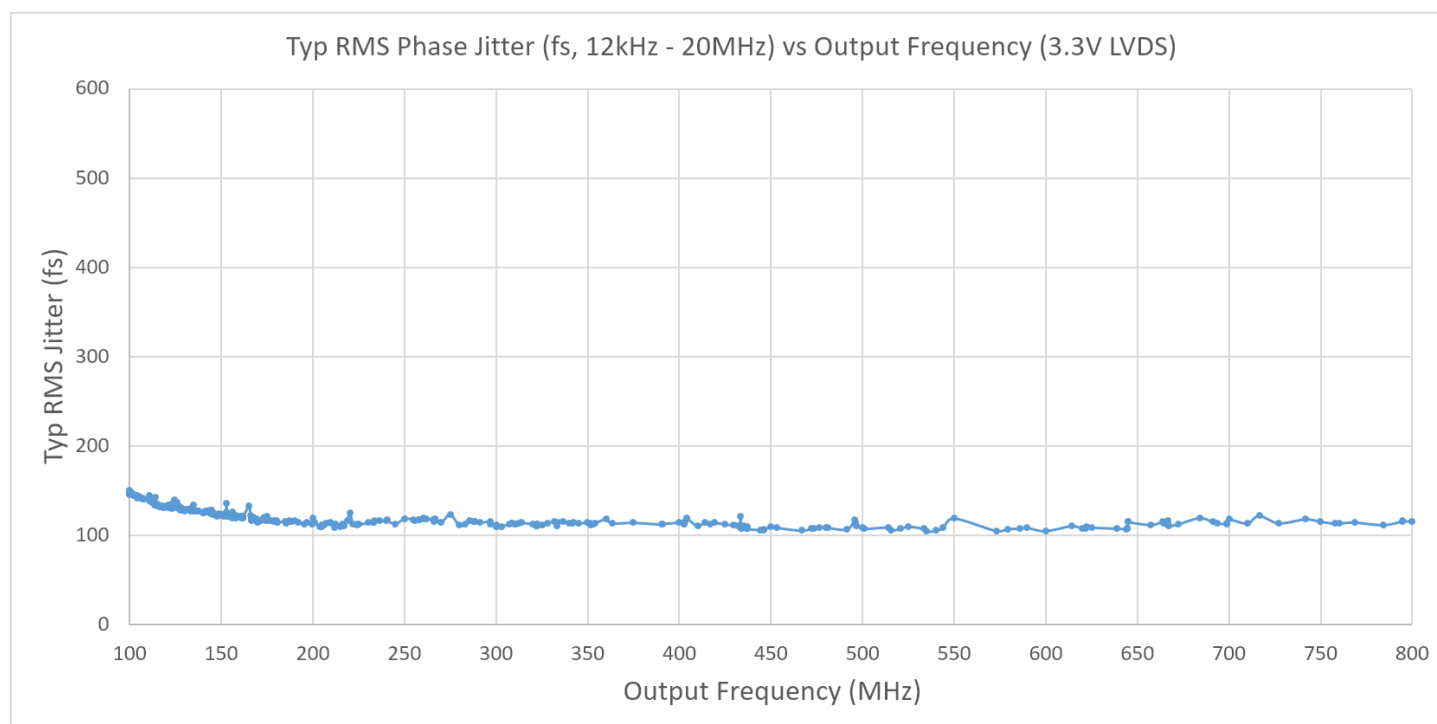
Parameter	Symbol	Test Condition/Comment	Min	Typ	Max	Unit
Phase Jitter (RMS, 12kHz - 20MHz) ¹ 3.2 x 5 mm, F _{CLK} ≥ 100 MHz	ϕ _J	Differential Formats	—	125	200	fs
		CMOS, Dual CMOS	—	200	—	fs
Phase Jitter (RMS, 12kHz - 20MHz) ¹ 5 x 7 mm, F _{CLK} ≥ 100 MHz		Differential Formats	—	150	200	fs
		CMOS, Dual CMOS	—	200	—	fs
Spurs Induced by External Power Supply Noise, 50 mVpp Ripple. LVDS 156.25 MHz Output	PSRR	100 kHz sine wave	—	-83	—	dBc
		200 kHz sine wave	—	-83	—	
		500 kHz sine wave	—	-82	—	
		1 MHz sine wave	—	-85	—	

Note:

1. Guaranteed by characterization. Jitter inclusive of any spurs.

Table 2.3. 3.2 x 5 mm Clock Output Phase Noise (Typical)

Offset Frequency (f)	156.25 MHz LVDS	200 MHz LVDS	644.53125 MHz LVDS	Unit
100 Hz	–110	–107	–99	dBc/Hz
1 kHz	–121	–120	–109	
10 kHz	–132	–130	–121	
100 kHz	–139	–137	–127	
1 MHz	–151	–149	–138	
10 MHz	–160	–161	–155	
20 MHz	–161	–162	–157	
Offset Frequency (f)	156.25 MHz LVPECL	200 MHz LVPECL	644.53125 MHz LVPECL	Unit
100 Hz	–113	–110	–100	dBc/Hz
1 kHz	–123	–120	–110	
10 kHz	–133	–130	–119	
100 kHz	–139	–137	–127	
1 MHz	–151	–149	–138	
10 MHz	–162	–166	–156	
20 MHz	–163	–167	–157	



Phase jitter measured with Agilent E5052 using a differential-to-single ended converter (balun or buffer). Measurements collected for >700 commonly used frequencies. Phase noise plots for specific frequencies are available using our free, online Oscillator Phase Noise Lookup Tool at www.silabs.com/oscillators.

Figure 2.1. Phase Jitter vs. Output Frequency

Table 2.4. Environmental Compliance and Package Information

Parameter	Test Condition
Mechanical Shock	MIL-STD-883, Method 2002
Mechanical Vibration	MIL-STD-883, Method 2007
Solderability	MIL-STD-883, Method 2003
Gross and Fine Leak	MIL-STD-883, Method 1014
Resistance to Solder Heat	MIL-STD-883, Method 2036
Moisture Sensitivity Level (MSL)	1
Contact Pads	Gold over Nickel
Note: 1. For additional product information not listed in the data sheet (e.g. RoHS Certifications, MDDS data, qualification data, REACH Declarations, ECCN codes, etc.), refer to our "Corporate Request For Information" portal found here: www.silabs.com/support/quality/Pages/RoHSInformation.aspx .	

Table 2.5. Thermal Conditions

Package	Parameter	Symbol	Test Condition	Value	Unit
3.2 × 5 mm 6-pin CLCC	Thermal Resistance Junction to Ambient	Θ_{JA}	Still Air, 85 °C	80.3	°C/W
	Thermal Resistance Junction to Board	Θ_{JB}	Still Air, 85 °C	50.8	°C/W
	Max Junction Temperature	T_J	Still Air, 85 °C	125	°C
5 × 7 mm 6-pin CLCC	Thermal Resistance Junction to Ambient	Θ_{JA}	Still Air, 85 °C	68.4	°C/W
	Thermal Resistance Junction to Board	Θ_{JB}	Still Air, 85 °C	52.9	°C/W
	Max Junction Temperature	T_J	Still Air, 85 °C	125	°C

Table 2.6. Absolute Maximum Ratings¹

Parameter	Symbol	Rating	Unit
Maximum Operating Temp.	T_{AMAX}	95	°C
Storage Temperature	T_S	–55 to 125	°C
Supply Voltage	V_{DD}	–0.5 to 3.8	°C
Input Voltage	V_{IN}	–0.5 to $V_{DD} + 0.3$	V
ESD HBM (JESD22-A114)	HBM	2.0	kV
Solder Temperature ²	T_{PEAK}	260	°C
Solder Time at T_{PEAK} ²	T_P	20–40	sec
Notes: 1. Stresses beyond those listed in this table may cause permanent damage to the device. Functional operation specification compliance is not implied at these conditions. Exposure to maximum rating conditions for extended periods may affect device reliability. 2. The device is compliant with JEDEC J-STD-020.			

3. Dual CMOS Buffer

Dual CMOS output format ordering options support either complementary or in-phase signals for two identical frequency outputs. This feature enables replacement of multiple XOs with a single Si540 device.

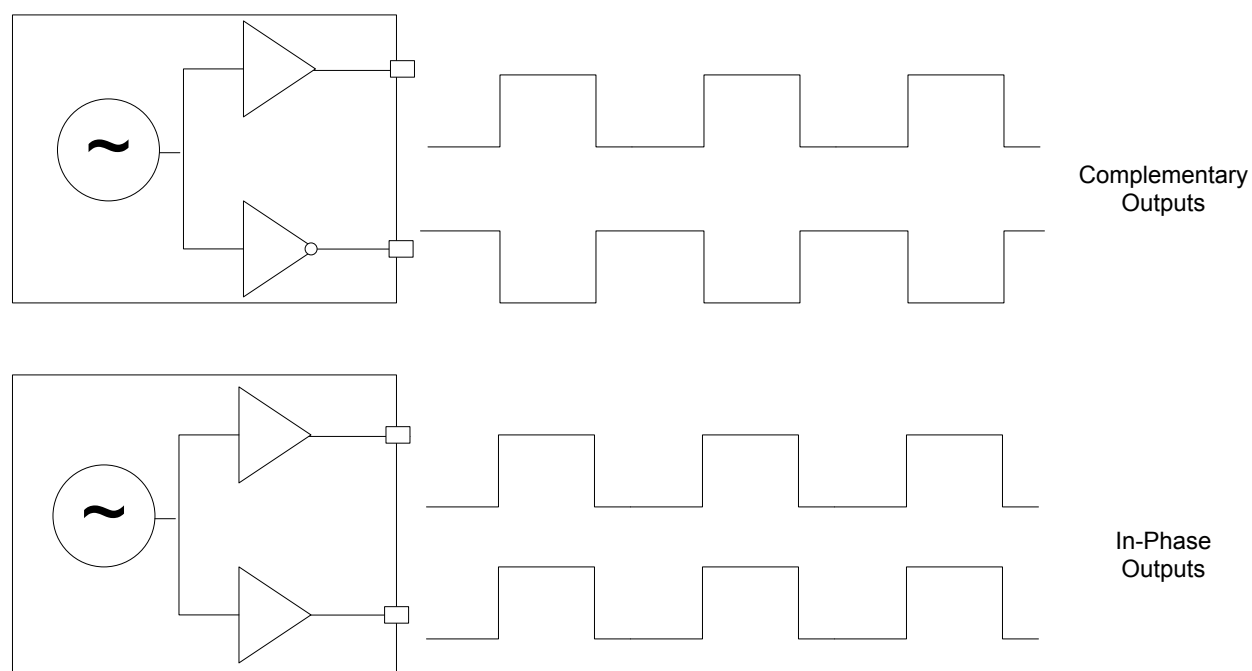
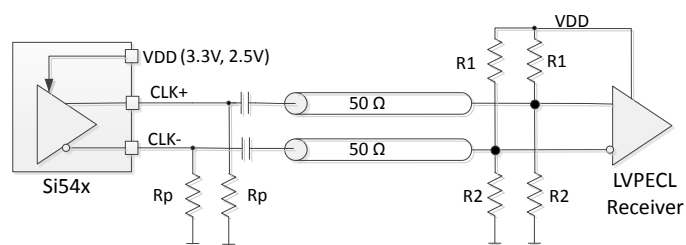


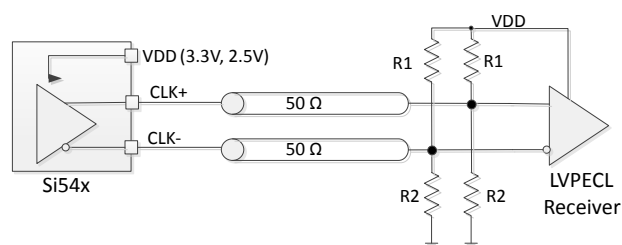
Figure 3.1. Integrated 1:2 CMOS Buffer Supports Complementary or In-Phase Outputs

4. Recommended Output Terminations

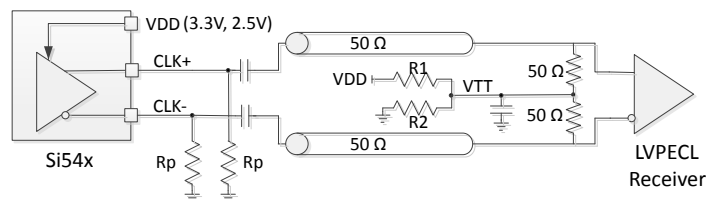
The output drivers support both AC-coupled and DC-coupled terminations as shown in figures below.



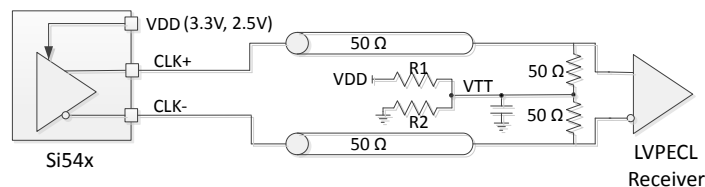
AC-Coupled LVPECL – Thevenin Termination



DC-Coupled LVPECL – Thevenin Termination



AC-Coupled LVPECL - 50 Ω w/VTT Bias

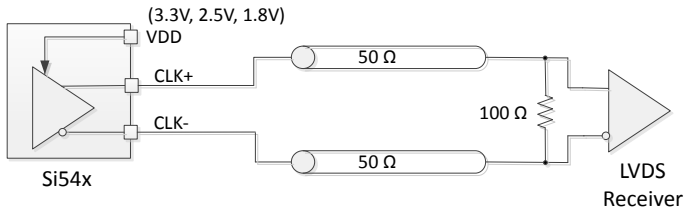


DC-Coupled LVPECL - 50 Ω w/VTT Bias

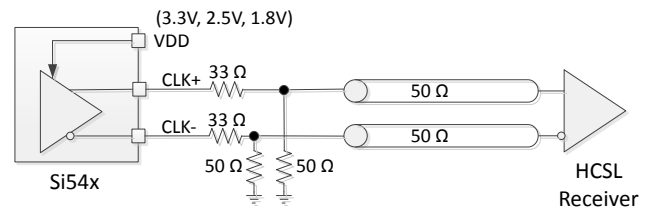
Figure 4.1. LVPECL Output Terminations

AC Coupled LVPECL Termination Resistor Values			
VDD	R1	R2	Rp
3.3 V	127 Ω	82.5 Ω	130 Ω
2.5 V	250 Ω	62.5 Ω	90 Ω

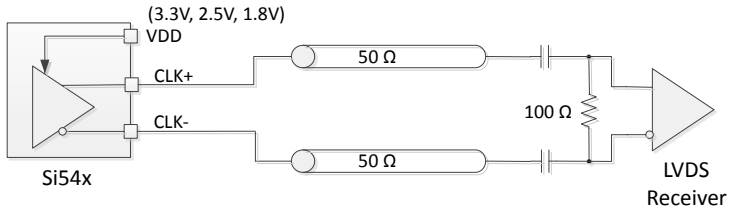
DC Coupled LVPECL Termination Resistor Values		
VDD	R1	R2
3.3 V	127 Ω	82.5 Ω
2.5 V	250 Ω	62.5 Ω



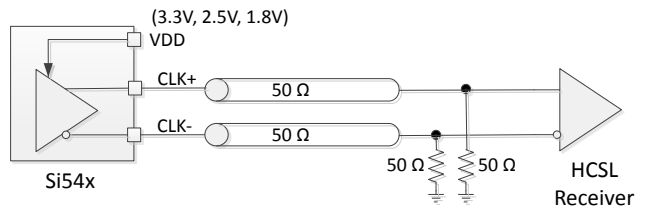
DC-Coupled LVDS



Source Terminated HCSSL

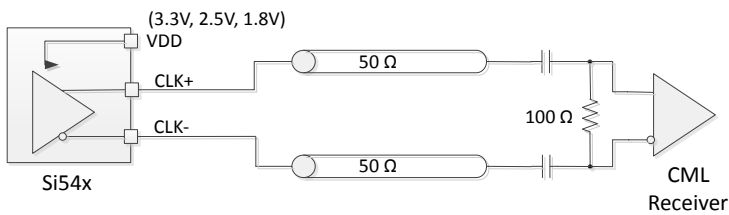


AC-Coupled LVDS

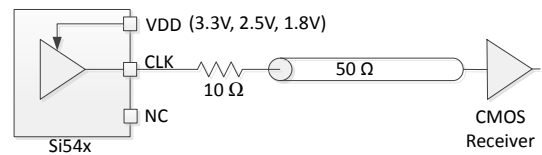


Destination Terminated HCSSL

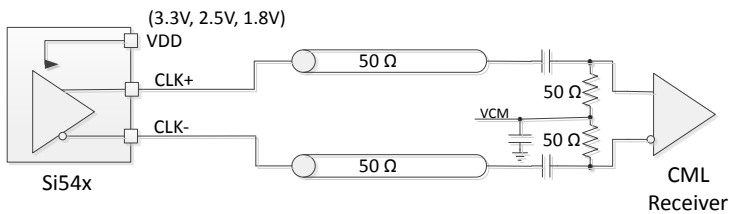
Figure 4.2. LVDS and HCSSL Output Terminations



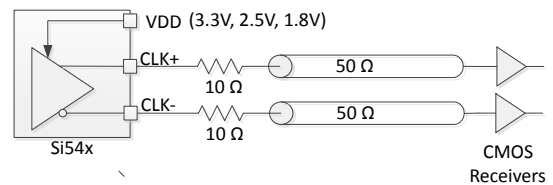
CML Termination without VCM



Single CMOS Termination



CML Termination with VCM



Dual CMOS Termination

Figure 4.3. CML and CMOS Output Terminations

5. Package Outline

5.1 Package Outline (5×7 mm)

The figure below illustrates the package details for the 5×7 mm Si540. The table below lists the values for the dimensions shown in the illustration.

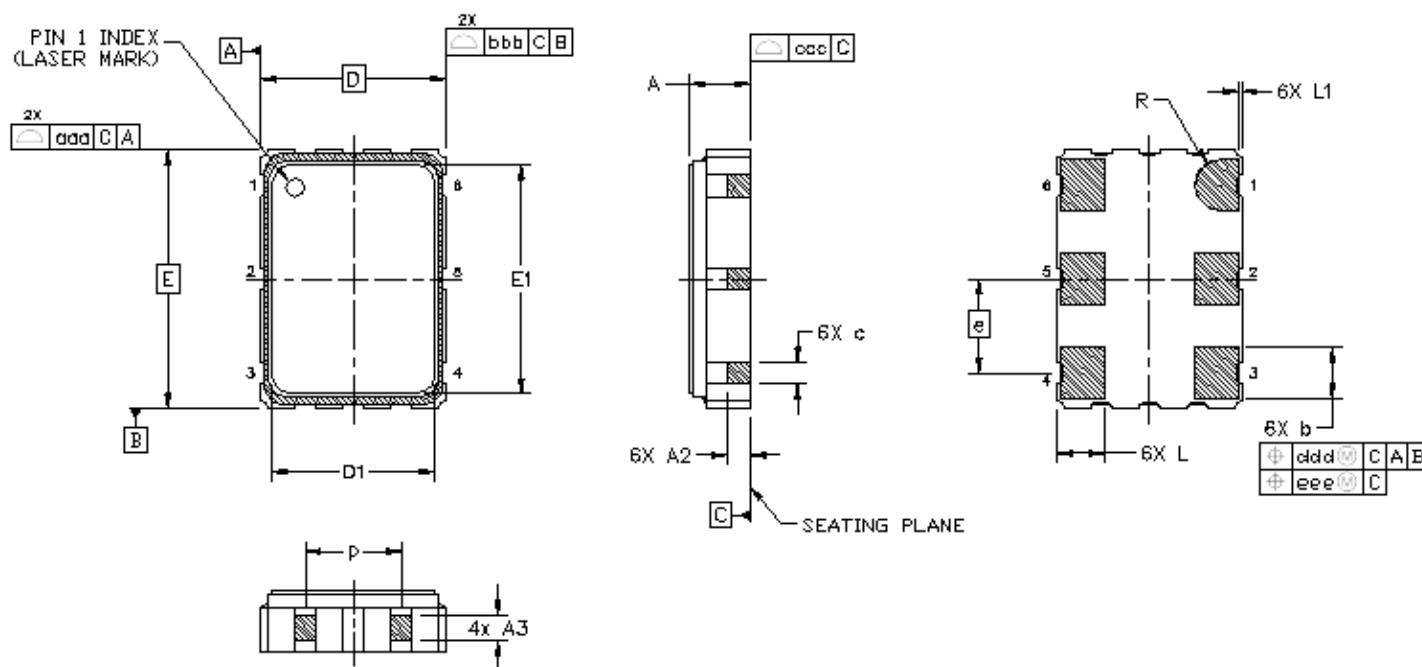


Figure 5.1. Si540 (5×7 mm) Outline Diagram

Table 5.1. Package Diagram Dimensions (mm)

Dimension	Min	Nom	Max	Dimension	Min	Nom	Max
A	1.13	1.28	1.43	L	1.17	1.27	1.37
A2	0.50	0.55	0.60	L1	0.05	0.10	0.15
A3	0.50	0.55	0.60	p	1.70	—	1.90
b	1.30	1.40	1.50	R	0.70 REF		
c	0.50	0.60	0.70	aaa	0.15		
D	5.00 BSC			bbb	0.15		
D1	4.30	4.40	4.50	ccc	0.08		
e	2.54 BSC			ddd	0.10		
E	7.00 BSC			eee	0.05		
E1	6.10	6.20	6.30				

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

6. PCB Land Pattern

6.1 PCB Land Pattern (5×7 mm)

The figure below illustrates the 5×7 mm PCB land pattern for the Si540. The table below lists the values for the dimensions shown in the illustration.

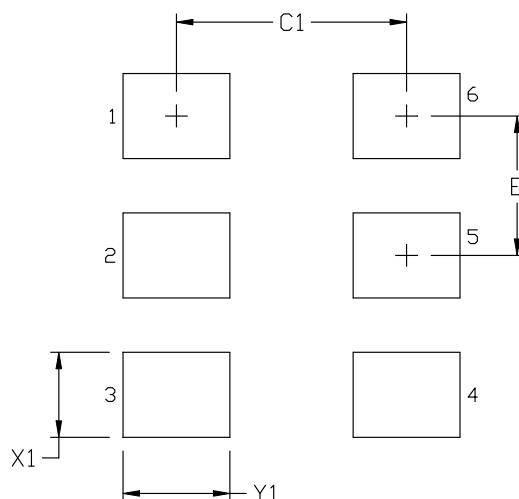


Figure 6.1. Si540 (5×7 mm) PCB Land Pattern

Table 6.1. PCB Land Pattern Dimensions (mm)

Dimension	(mm)
C1	4.20
E	2.54
X1	1.55
Y1	1.95

Notes:

General

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1.

Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

6.2 PCB Land Pattern (3.2×5 mm)

The figure below illustrates the 3.2×5.0 mm PCB land pattern for the Si540. The table below lists the values for the dimensions shown in the illustration.



Figure 6.2. Si540 (3.2×5 mm) PCB Land Pattern

Table 6.2. PCB Land Pattern Dimensions (mm)

Dimension	(mm)
C1	2.60
E	1.27
X1	0.80
Y1	1.70

Notes:

General

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μ m minimum, all the way around the pad.

Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1.

Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7. Top Marking

The figure below illustrates the mark specification for the Si540. The table below lists the line information.

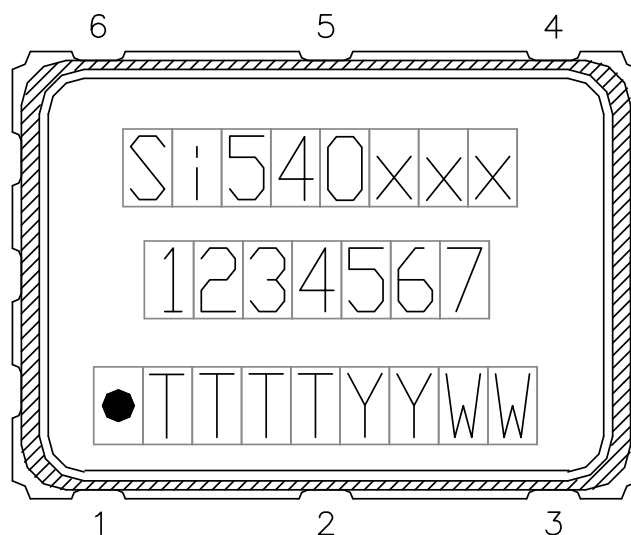


Figure 7.1. Mark Specification

Table 7.1. Si540 Top Mark Description

Line	Position	Description
1	1–8	"Si540", xxx = Ordering Option 1, Option 2, Option 3 (e.g. Si540AAA)
2	1–7	Frequency Code (e.g. 100M000 or 6-digit custom code as described in the Ordering Guide)
3	Trace Code	
	Position 1	Pin 1 orientation mark (dot)
	Position 2	Product Revision (B)
	Position 3–5	Tiny Trace Code (3 alphanumeric characters per assembly release instructions)
	Position 6–7	Year (last two digits of the year), to be assigned by assembly site (ex: 2017 = 17)
	Position 8–9	Calendar Work Week number (1–53), to be assigned by assembly site

8. Revision History

Revision 1.0

July 2018

- Added 20 ppm total stability option.

Revision 0.75

March, 2018

- Added 25 ppm total stability option.

Revision 0.71

December 11, 2017

- Added 5x7 package and land pattern.

Revision 0.7

June 27, 2017

- Initial release.

ClockBuilder Pro

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Silicon Laboratories Inc.
400 West Cesar Chavez
Austin, TX 78701
USA

<http://www.silabs.com>